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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re application of
RUTTEN, IVO WILHELMUS
JOHANNES MARIE
Serial: 10/023,537

Atty. Docket
US 018205

MAY 24 2004

Group Art Unit: 2133

Filed: 12/18/2001

Examiner: TABONE JR, JOHN J

MICROPROCESSOR-BASED PROBE FOR INTEGRATED CIRCUIT TESTING

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE UNDER 37 CFR 1.111

Sir:

Responsive to the Office Action of 04/23/2004, please amend this application as follows: